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## How to image and count nanostructured graphene layers?

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The presentation will begin with a brief introduction of graphene: what it is, why it is fascinating, and how to fabricate it. This will be followed by an overview of various optical/physical probe techniques in imaging and counting graphene layers. This overview will include concise discussions on the optical detection of reflection/transmission, phase-contrast microscopy (PCM), differential interference contrast microscopy (DICM), atomic force microscopy (AFM), and Raman spectroscopy. Finally, a new attempt to image and count few-layer graphene (FLG) with high reliability as well as repeatability using surface plasmon resonance (SPR) will be presented.